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Appl. No. 10/003,258
April 5, 2005

AMENDMENTS TO THE CLAIMS:

*PLEASE ENTER
WM H/15/2005*
This listing of claims will replace all prior versions, and listings, of claims in the application:

1-3. (Canceled)

4. (Previously presented) An insulator capacitance analyzer for analyzing C-V characteristics of a first MIS structure having unknown capacitance, comprising:
a capacitance structure having known capacitance and configured so as to be serially connectable to the first MIS structure;
a measuring section for measuring synthesis capacitance of the serially-connected first MIS structure and capacitance structure;
a plurality of capacitance structures each having known capacitance and configured so as to be serially connectable to the first MIS structure; and
a switch for selecting one of the plurality of capacitance structures as the capacitance structure.

5-9. (Canceled)

10. (Previously presented) An insulator capacitance analyzer for analyzing C-V characteristics of a first MIS (Metal/Insulator/Semiconductor) structure, comprising:
a capacitance structure having a known capacitance and serially connected to the first MIS structure;

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a measuring section for measuring a synthesis capacitance of the serially-connected first MIS structure and the capacitance structure; and

a plurality of capacitance structures each having known capacitance and configured so as to be serially connectable to the first MIS structure; and a switch for selecting one of the plurality of capacitance structures as the capacitance structure.